

FORM PTO-1449		Atty. Docket: H60-103 US		GAU: 3920				
LIST OF PRIOR ART CITED BY APPLICANT		Applicant(s): Wiki, et al						
		Serial No.: 10/047,530		Filed: October 23, 2001				
<u>U.S. PATENT DOCUMENTS</u>								
EI*		Document Number	Date	Name	Class	Sub-class	Filing Date	
<input checked="" type="checkbox"/>	AA	3,354,022	11/21/67	Dettre, et al				
<input checked="" type="checkbox"/>	AB	5,694,247	12/02/97	Ophey, et al				
<input checked="" type="checkbox"/>	AC	5,755,501	05/26/98	Shinohara, et al				
<input checked="" type="checkbox"/>	AD	6,031,951	02/29/00	Stiens				
	AE	6,177,129 B1	01/23/01	Wagner, et al				
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
<u>FOREIGN PATENT DOCUMENTS</u>								
		Document Number	Date	Country	Class	Sub-class	Translated	
							YES	NO
<input checked="" type="checkbox"/>	AL	0 509 343 A2	04/03/92	Europe				
<input checked="" type="checkbox"/>	AM	1 040 874 A2	10/04/00	Europe				
<input checked="" type="checkbox"/>	AN	1 096 274 A2	05/02/01	Europe				
<input checked="" type="checkbox"/>	AO	2 050 652	04/20/72	Germany				
<input checked="" type="checkbox"/>	AP	WO 96/04123	02/15/96	WIPO				
<u>OTHER PRIOR ART (including Author, Title, Date, Pertinent Pages, etc.)</u>								
<input checked="" type="checkbox"/>	AQ	Article from J. Opt. Soc. Am. A., Vol. 11, No. 10, October, 1994 - Artificial Uniaxial and Biaxial Dielectrics with Use of Two-Dimensional Subwavelength Binary Gratings, Grann, et al, Pgs. 2695-2703						
	AR							
	AS							
	AT							
Examiner: FAYEZ ASSAF				Date Considered: 9/4/04				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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El*		Document Number	Date	Name	Class	Sub-class	Filing Date	
	AA/2							
	AB/2							
	AC/2							
	AD/2							
	AE/2							
	AF/2							
	AG/2							
	AH/2							
	AI/2							
	AJ/2							
	AK/2							
<u>FOREIGN PATENT DOCUMENTS</u>								
		Document Number	Date	Country	Class	Sub-class	Translated	
							YES	NO
P	AL/2	WO 01/02839 A1	01/11/01	WIPO				
	AM/2							
	AN/2							
	AO/2							
	AP/2							
<u>OTHER PRIOR ART (including Author, Title, Date, Pertinent Pages, etc.)</u>								
	AQ/2							
	AR/2							
	AS/2							
	AT/2							
Examiner: FAYEZ ASSAF		Date Considered: 9/5/04						
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